

Supplementary information

Atomic force microscopy observation of surface morphologies and measurements of local contact potential differences of amorphous solid water samples deposited at 15 and 100 K

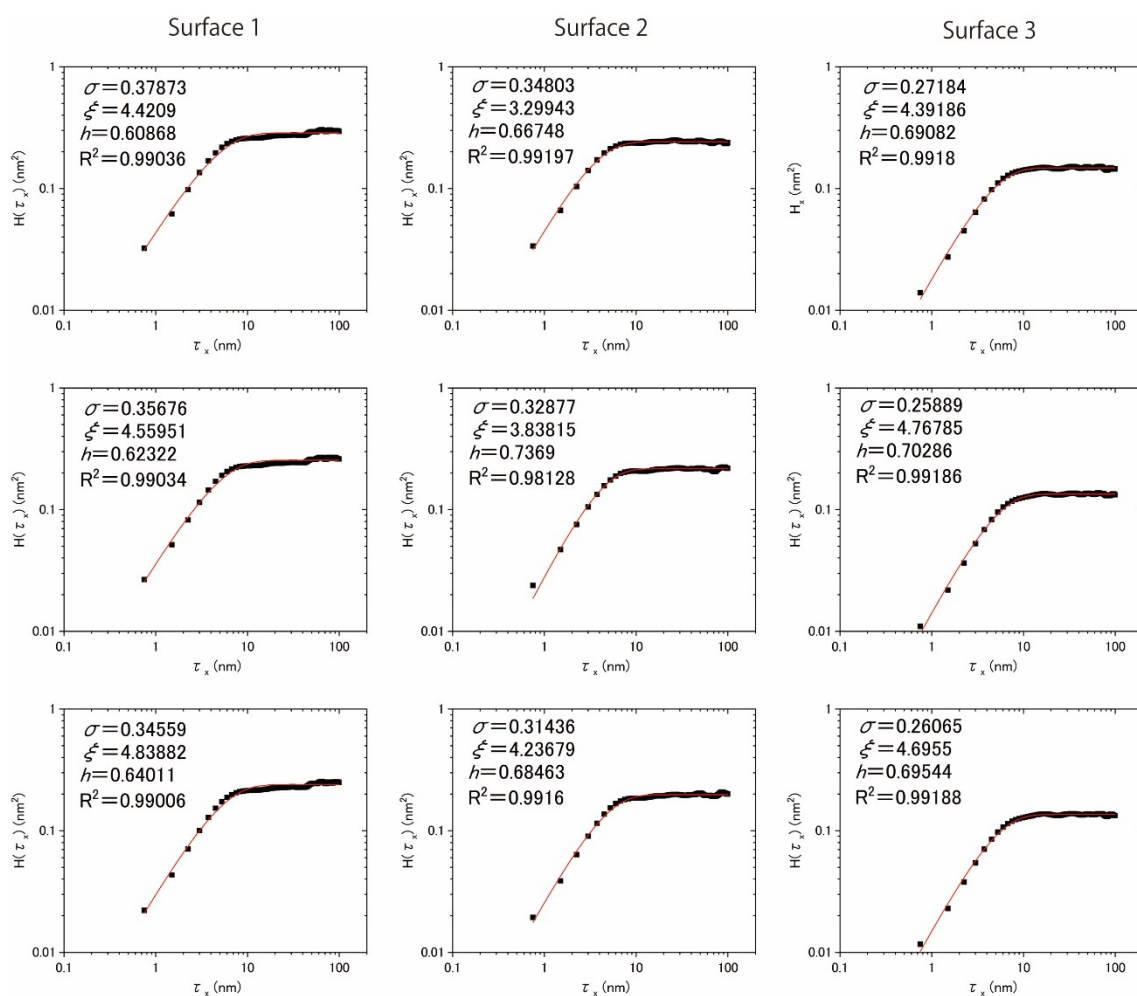
Takuto Tomaru, Hiroshi Hidaka, Akira Kouchi Naoki Watanabe

Institute of Low Temperature Science, Hokkaido University, Sapporo, 060-0819, Japan

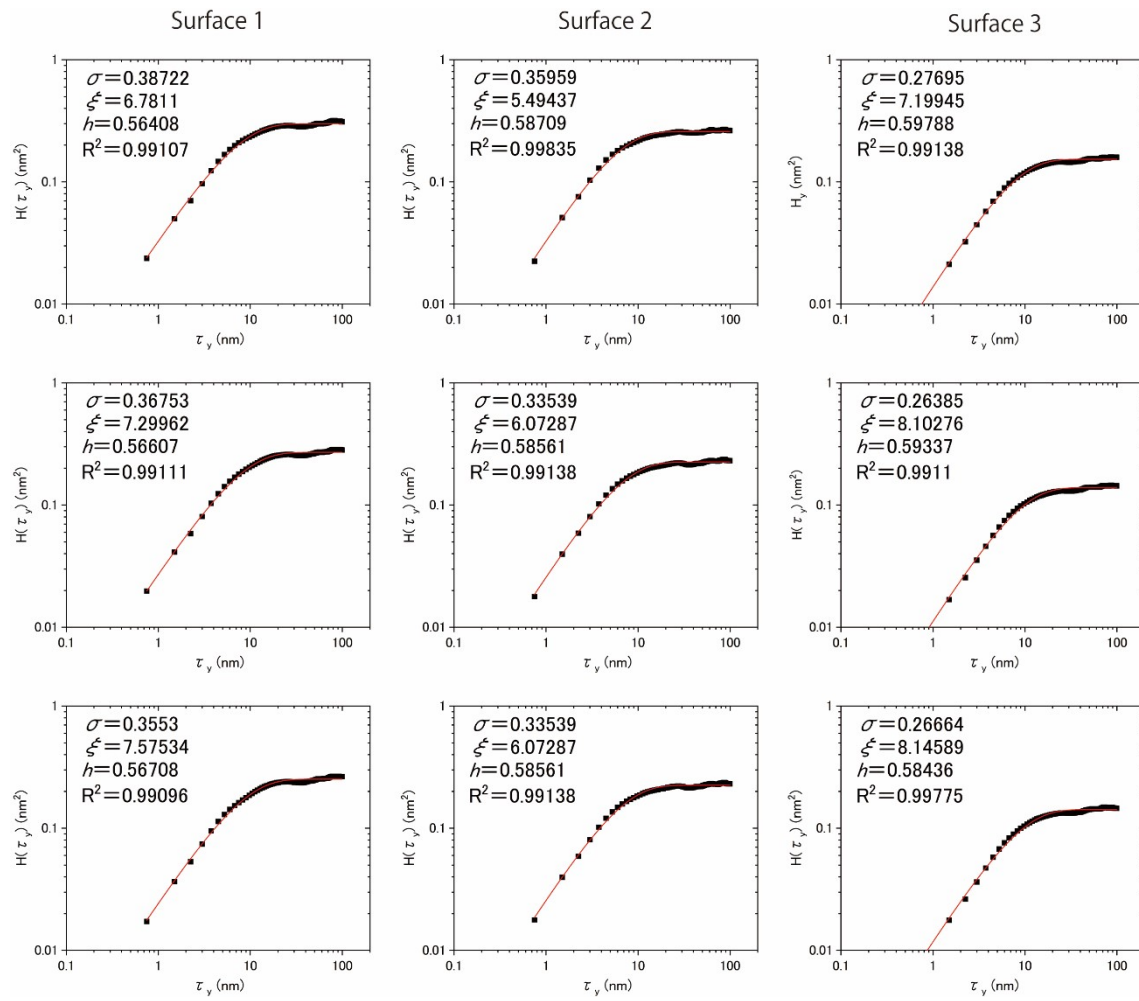
All fitting data used for the derivation of averaged values in Table 1

Topographic data were obtained at three different surface areas for each temperature. The measurements were conducted three times at 15 K and four times at 100 K for each surface.

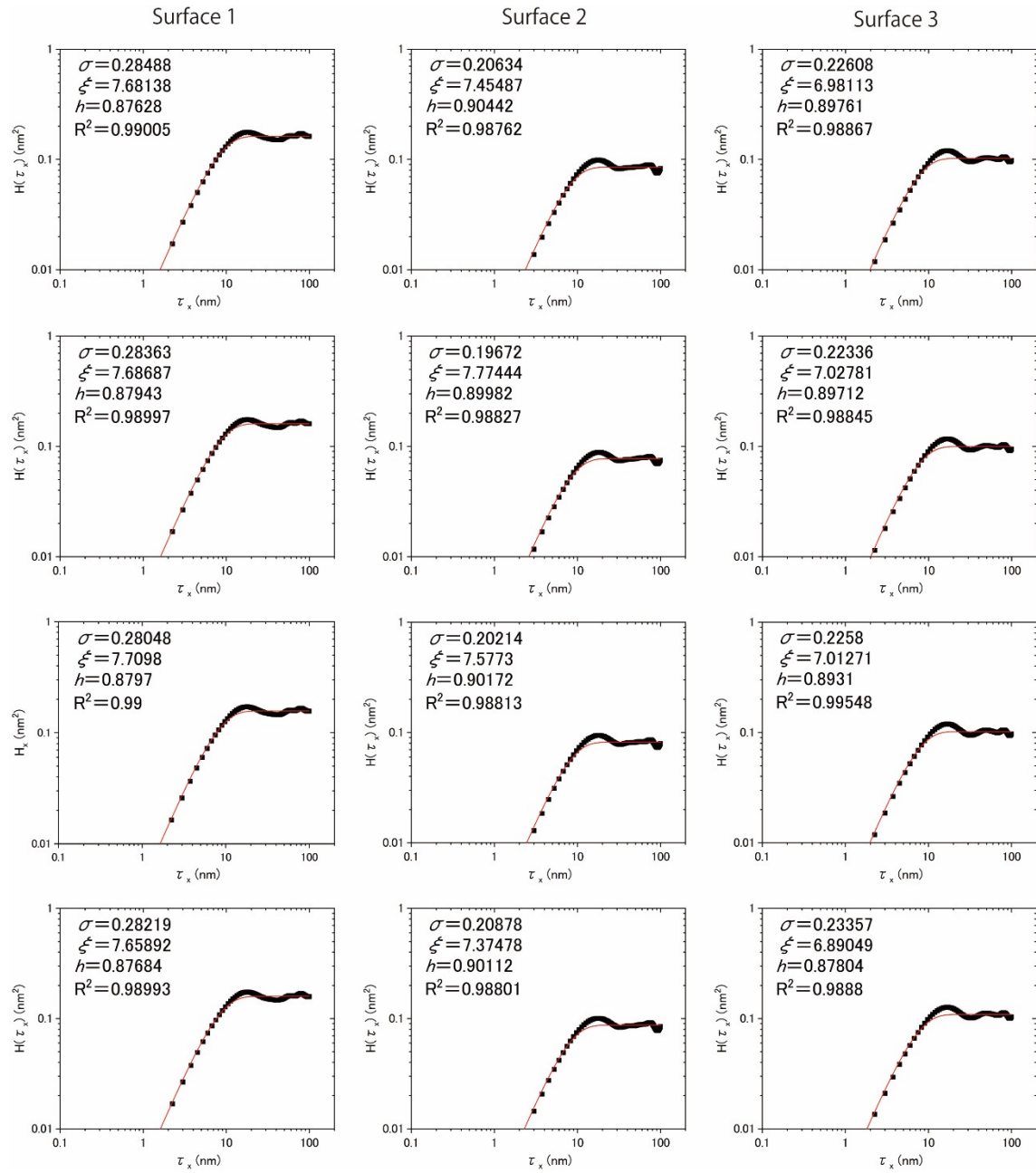
X-direction analysis at 15K



Y-direction analysis at 15K



X-direction analysis at 100K



Y-direction analysis at 100K

